

<b>Notice of References Cited</b>	Application/Control No. 09/989,530		Applicant(s)/Patent Under Reexamination NAKAI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,950,191	4-1976	Ito et al.	148/330
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English abstract of Japanese publication 2000144330A, Derwent 416079, May 26, 2000
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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